



Performance of the X-ray PSD based on the MWPC

Position sensitive detector (PSD) Multi-wire proportional chamber (MWPC)

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Introduction – X-ray

X선(X-Rays)으로 처음 촬영한

In 1895, Wilhelm Conrad Roentgen (GE) discovered the X-ray.







wavelength :0.01 ~ 100 Angstrom



< general properties >

- X-ray detection method
 - Imaging 0
 - Fluorescence (ZnS, CdS, Nal) 0
 - Ionization 0
- Light speed in vacuum
- Diffraction like particle
- Reflection index ~ 1

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(impossible to focus the X-ray)
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medical imaging & material experiment due • to the high transparency

Introduction – X-ray diffraction

In 1912, Laue (GE) succeeded the X-ray diffraction experiment . X-ray diffracts when its wavelength is same as the distance in between atoms.



In 1913, Bragg (UK) makes Laue's diffraction formula more simply.



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Introduction - SAXS

- Small angle X-ray scattering (SAXS):
 - research the shape and size of the high molecular materials.
 - role of PSD: to measure the scattered pattern.



$$q = \frac{2\pi}{d} = \frac{4\pi\sin\theta}{\lambda}$$

q: scattering vector
d: distance between the surface of atoms
λ: wavelength
2Θ: scattering angle



SAXS at Hannam University

Energy range of photon for diffraction and scattering experiment: $5 \sim 30$ keV

Photo-electric effect Wavelength of X-ray: 1.54 Å at 8.04 keV



< X-ray generator >

Rigaku rotating anode 3 kW filament 40 kV, 70 mA

< Focusing mirror >

Osmic Confocal Max-Flux Source-focus distance: I 200 mm

Introduction - PSD

Why is MWPC attracted than the semiconductor detector?

- Multi-wire proportional chamber (MWPC)
 - single counting method

<strength>

- high X-ray detection efficiency
- good position linearity
- geometrical flexibility
- fast DAQ
- low production cost

<weakness>

- relatively poor position resolution compared to SDAD.
- poor rate capability

- Silicon diode array detector (SDAD) or charge-coupled device (CCD)
 - charge accumulation method

<strength>

- good rate capability
- good position resolution

<weakness>

- high background
- narrow dynamic range
- poor time resolution
- slow DAQ

Operation of X-ray PSD

- Energy range of photon for diffraction and scattering experiment: 5 ~ 30 keV
- Photo-electrical effect creates the photo-electron or Auger electron.
- Average ionization energy of noble gas (Ar, Kr, Xe): ~ 30 eV
 - number of produced electron-ion pairs: ~160 at 5 keV

~267 at 8 keV

~1000 at 30 keV

<MWPC>



Detector configuration



Winding Machine







Picture of X-ray PSD







Delay-line readout method





Data acquisition

Inductor (145 nH) & capacitor (56 pF)

$$Z = \sqrt{\frac{L}{C}} = 51\Omega$$
$$t = \sqrt{LC} = 2.85ns$$

• Total delay time: 170 ns





Operational region

- Ar + C_2H_6 + CF_4 at 1.5 atm
- Drift voltage: I 200 V
- Fe-55: 6.4 keV, 10 mCi
 - (half life time : 2.744 y)
- Source to PSD: 45 cm







Position resolution

- •Ar I.5 atm
- Drift voltage: I 200 V
- High voltage: +2425 ~ 2575 V
- Voltage step: +50 V

• Fe-55 (KAERI)





Uniformity

- •Ar I.5 atm
- Drift voltage: I 200 V
- High voltage: +2525 V
- Fe-55 (KAERI)
- Source to PSD: 45 cm
- Time: 21600 sec (6 hours)







Operational region

Xe + C_2H_6 + CF_4 at 1.55 atm Silver behenate (SB): standard sample for SAXS



- Two plots are shown the equivalent trend.
- BKG rate has decreased and has been stable.

BKG & SB at SAXS

- Xe 1.55 atm
- Drift voltage: I 200 V
- HV: +3050 V

BKG rate has decreased.

18 cps at the beginning.
14 cps after 24 hours.
11 cps after 72 hours.





The first peaks can be different due to beam focusing and fluctuation of beam flux.

The second and third peaks correspond to the old data.

- Xe 1.55 atm
- Drift voltage: I 200 V
- 360 trial
- Total time: ~ 5040 sec (84 min)
- High voltage: +3050 V
- sample: LDPE

X-ray fluctuation



Counting rate shows not only some coincidence with the on/off of the cooler but also it presents unmatched period.

Introduction - XICS

- X-ray imaging crystal spectrometer (XICS)
 - to measure ion temperatures in the tokamak device.

Doppler-broadening

Movement of the center wavelength (spherically bent crystal)



Ar is injected in the tokamak.

He-like Ar (Ar XVII, Ar¹⁶⁺) has only two electrons due to the high energy plasma.

Ar¹⁶⁺ and plasma thermally equilibrated.

Ar¹⁶⁺ emits the X-ray.

 $\Delta \lambda = \lambda_0 \sqrt{\frac{kT}{mc^2}}$

 λ_0 : center wavelength of the spectrum k : Boltzmann constant

Phys. Rev. Lett. 42 304 (1979) M. Bitter et al. Rev. Sci. Instrum. 70, 1 (1999) M. Bitter et al. J. K. Cheon, Ph.D. thesis, Kyungpook national university, (2008)

Doppler-Broadening: the spectral lines are broaden caused by a distribution of velocities of atoms or molecules.



3.9494 Å 3.9944 Å



Fabricated PSD at KAERI: part I



ID & 2D X-ray PSD

2D curved X-ray PSD

Fabricated PSD at KAERI: part II



ID Neutron PSD



Neutron Monitor



2D Large Neutron PSD for SANS

Summary

- Many kinds of PSD have been producing at KAERI.
 - Small angle X-ray scattering (SAXS)
 - X-ray imaging crystal spectrometer (XICS)
 - Neutron monitor
 - Neutron diffraction
 - Small angle neutron scattering (SANS)

• PSD

- Low production cost
- Large effective area
- Geometrical flexibility
- Fast DAQ
- Good position resolution
- Sensitivity depending on gas and energy